

Revisit ISI_RES Specification for 100Gbase CR

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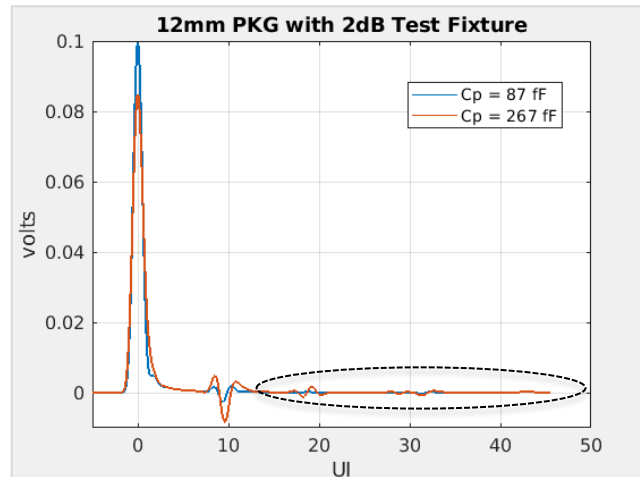
For IEEE 802.3ck Ad-Hoc

Outlines

- Background
- TX Specifications: KR vs CR
- Feasibility of Current Np & ISI_RES Values
- Conclusion & Proposal

Background

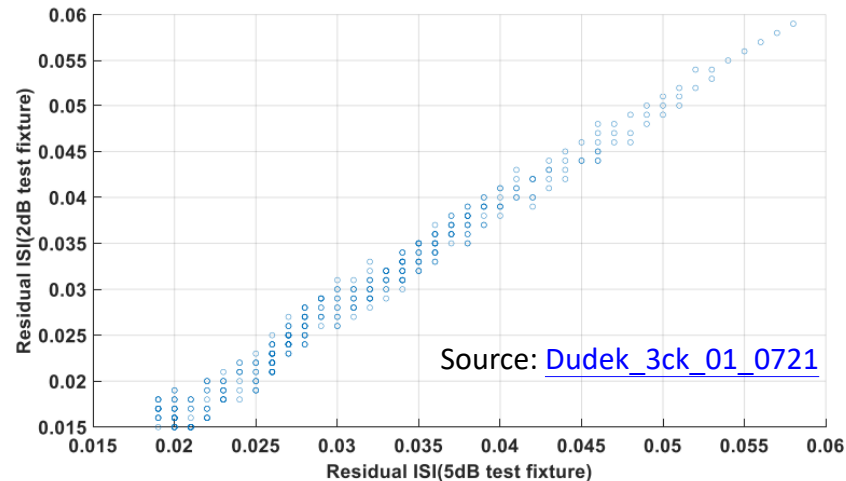
- [Dudek_3ck_adhoc_01_0428](#) & [Dudek_3ck_01_0521](#) showed that the transmitters with similar dERL, SNDR, dRpeak, and dVf have very different system performance
 - E.g., existing KR spec allowed a 12mm package with $C_p=0.267\text{pF}$ to pass the TX specifications
- In [Dudek_3ck_01_0721](#), it was shown that energy outside the main pulse can interact with reflections in the channel
 - For high C_p case, more DFE taps or banks of floating taps are required than the current KR reference RX has
 - Additional ISI_RES spec was proposed for 802.3ck KR to differentiate between these transmitters



Background

- According to draft 3.0 comment #237, ISI_RES with max value of -30dB was added to CR specification based on
 - [Dudek_3ck_01_0721](#) showed that residual ISI won't be affected by test fixture (TF) loss
 - 1 dB gap to distinguish Pmax difference between KR & CR

	TX SNDR spec ($N_p = 200$)	RES_ISI spec ($N_p = 11$)
KR	32.5	-31
CR	31.5	-30



Necessity of ISI_RES Spec?

- Types of transmitter ERL spec
 - KR (TP0v): difference between measured and reference values
 - CR (TP2): specific ERL value
- Definitions of ERL & ISI_RES are kind of similar
 - Transmitter specifications at TP2

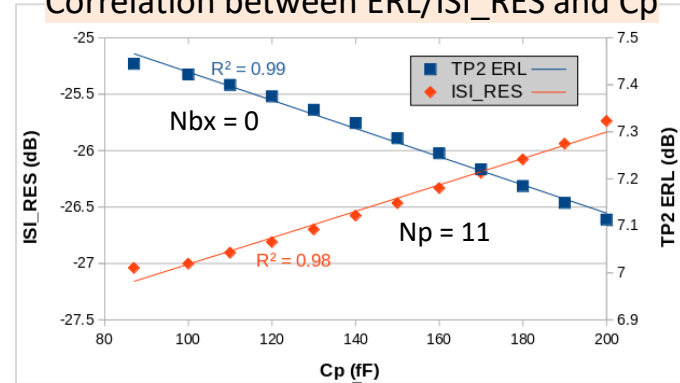
	Parameters
ERL	Nbx = 0
ISI_RES	Np = 11

- ERL under Nbx = 0 is sufficient to cover the reflection issue
 - Correlation between ERL and Cp is strong
 - Different Cp values represent different reflection levels

Table 162-13—Transmitter and receiver ERL parameter values

Parameter	Symbol	Value	Units
Transition time associated with a pulse	T_f	0.01	ns
Incremental available signal loss factor	β_x	0	GHz
Permitted reflection from a transmission line external to the device under test	ρ_x	0.618	—
Length of the reflection signal	N	800	UI
Equalizer length associated with reflection signal	N_{bx}	0	UI
Tukey window flag	n_v	1	—

Correlation between ERL/ISI_RES and Cp

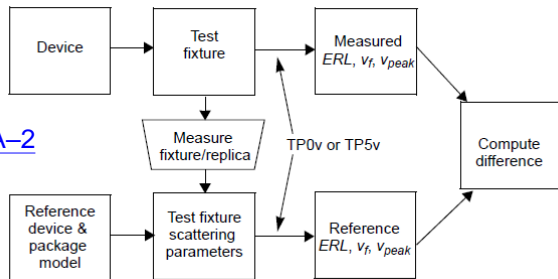


* TP0-TP2: "C2M_Z100_IL12_WC-BOR_H_L_H_THRU.s4p",
[mellitz_3ck_01_0518_C2M](#)

TX specifications: KR vs CR (1/2)

- KR specification at TP0v mainly defines the difference between measured and reference values of transmitter
 - [wu_3ck_adhoc_01_093020](#) & [li_3ck_adhoc_01_063021](#) evaluated TP0v dERL value based on the variations of Z_p , Z_c , & R_d
 - [Dudek_3ck_01_0721](#) proposed additional ISI_RES spec to guarantee the whole link performance
- Recall KR TX measurement method

Draft 3.0 Figure 163A-2

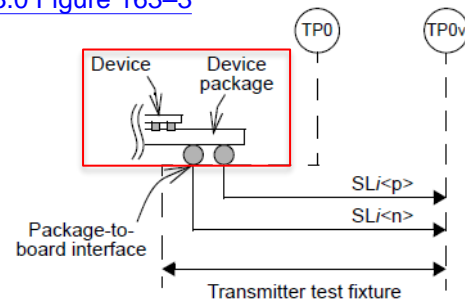


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KR TX TF & test points

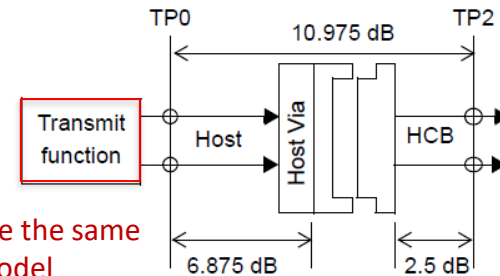
Draft 3.0 Figure 163-3

KR



Draft 3.0 Figure 162A-3

CR



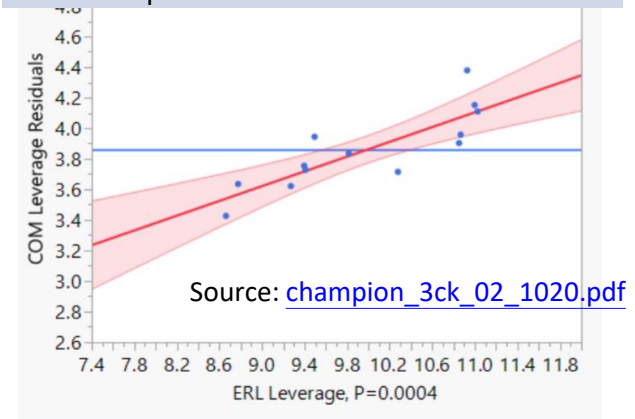
KR & CR share the same ref. device model

TX specifications: KR vs CR (2/2)

- TP2 ERL specifies the reflections from TX device to TP2
 - ERL calculated based on $N_{bx} = 0 \rightarrow$ ISI_RES spec & TX ERL spec overlapping
 - Unlike KR, the existence of transition vias & connector within TP0-TP2 makes large C_p relatively less dominated
 - CR ERL value determined based on the comprehensive analysis of
 - Published channels that representative of 100G host designs
 - Relationship between ERL and COM
 - Please also refer to [kochuparambil_3ck_03b_1020](#), [champion_3ck_02_1020.pdf](#), and draft 1.3 Comment #3 & #114 for details
- \rightarrow ISI_RES spec is unnecessary for 802.3ck CR**
- **Option A: Remove ISI_RES specification from 802.3ck CR (Table 162.10)**

	KR	CR
Effective return loss (dB)	$dERL > -3$	$ERL > 7.3$
Steady-state voltage (V)	$dV_f > 0$	$0.387 < V_f < 0.6$
Linear fit pulse peak ratio	$dR_{peak} > 0$	$R_{peak} > 0.397$

Relationship between ERL and COM is observed



Feasibility of Current Np & ISI_RES Values

- Very different channel characteristics between TP0-TP0v & TP0-TP2

	TX SNDR spec (Np = 200)	RES_ISI spec (Np = 11)	TF loss (dB)	TX ERL spec (dB)
KR	32.5	-31	1.7-5	dERL > -3
CR	31.5	-30	< 10.975	ERL > 7.3

- From the perspective of TF loss

- For Np = 11, ~3.5 dB residual ISI caused by TF loss
- Np > 11 & ISI_RES > -30 dB are required to distinguish residual ISI from TF loss & reflection

- From the perspective of reflection

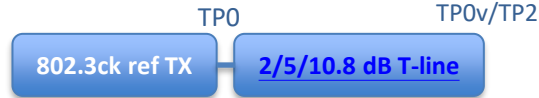
- Channel characteristics of TP0-TP2 make ISI_RES more complicated to be specified
- ISI_RES will be affected by not just TF loss but also impedance discontinuities within TF
- Change Np = 11 → 18 & ISI_RES (max) = -30 → -29 dB



KR vs CR: from the Perspective of IL

- Experiments for evaluating TF loss impacts

- $Z_p = 12 \text{ mm}$
- $C_p = [87 \text{ 100:10:300}] \text{ fF}$
- Other parameters shown in [appendix](#)

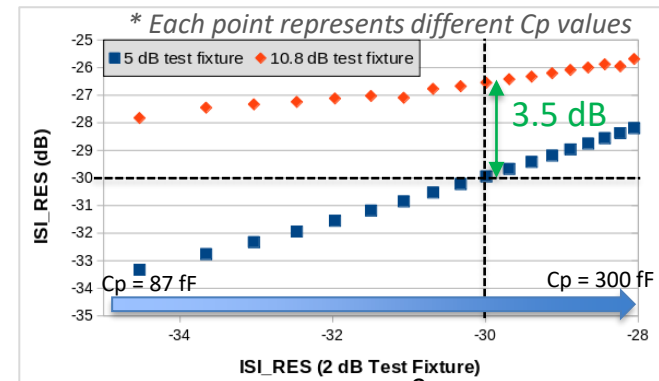
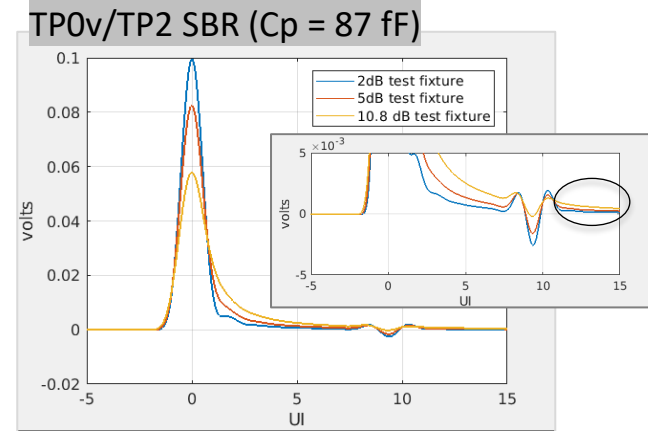


- Energy outside main cursor caused by TF loss will let CR suffer severe fitted error

	TX SNDR spec ($N_p = 200$)	RES_ISI spec ($N_p = 11$)	TF loss (dB)
KR	32.5	-31	1.7-5
CR	31.5	-30	< 10.975

- Residual ISI will be affected by TF loss if channel tails > N_p
- Need to distinguish residual ISI from TF loss or reflection

- Current values of N_p & ISI_RES are unreasonable**

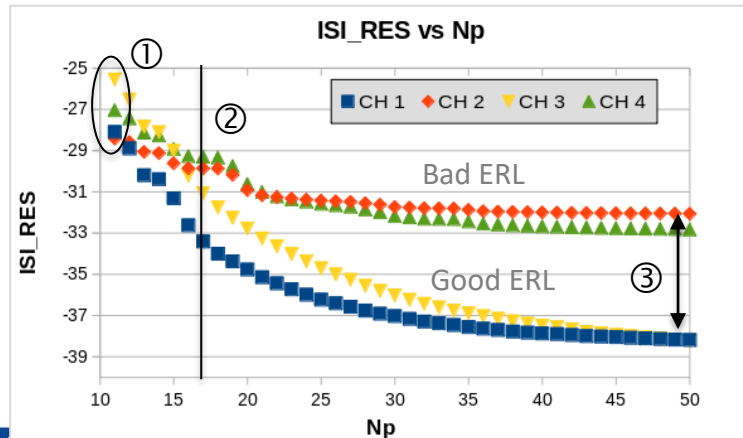


KR vs CR: from the Perspective of Reflection (1/2)

* 12mm PKG & Cp = 87 fF

- Experiments for evaluating reflection impacts within TF
 - Choose 2 pairs of channels with similar IL but very different ERL
 - TF (TP0-TP2) information listed in [appendix](#)
 - COM spreadsheet shown in [appendix](#)
 - TX FIR set to Preset 1
- ISI_RES will be affected by not just TF loss but also impedance discontinuities within TF

	TF (TP0-TP2) loss	TP2 ERL
CH 1	9.07 dB	10.61 dB
CH 2	9.29 dB	7.05 dB
CH 3	11.15 dB	10.92 dB
CH 4	11.15 dB	7.44 dB
802.3ck CR	< 10.975 dB	> 7.3 dB



- CH 1 & 3 with similar ERL but different TF loss contribute very different ISI_RES under Np = 11
 → Np = 11 is insufficient to cover TF loss-induced ISI
- Necessity to differentiate TFs with different ERL conditions
 → Np = 17 at least
- Though Np = 50 is long enough to cover channel tails, the impedance discontinuities within TP0-TP2 also make impacts on ISI_RES
 → ISI_RES value at TP2 is more complicated to be specified

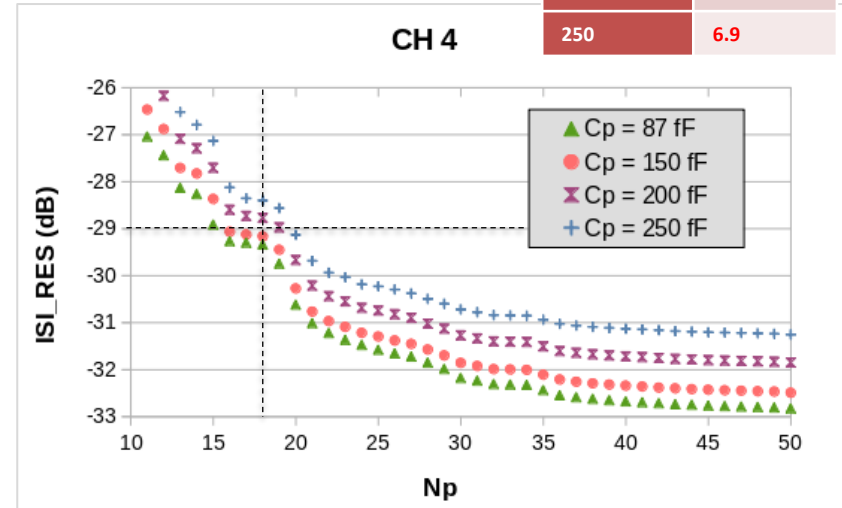


KR vs CR: from the Perspective of Reflection (2/2)

- **Criteria of determining N_p & ISI_RES**
 - CH 4 with more critical TF conditions is chosen for analysis
 - If N_p too small, severe fitted error within channel tails is inevitable
 - If N_p too large, the existence of ISI_RES spec is less significant
 - $N_p > 17$ is required to differentiate TFs with different ERL conditions (from the result of P.10)
 - Ability to filter out bad ERL cases
- **Proposed changes for N_p & ISI_RES**
 - $N_p = 11 \rightarrow 18$
 - $ISI_RES = -30 \rightarrow -29$ dB
- **Option B: Change N_p from 11 \rightarrow 18 & ISI_RES (max) from -30 dB \rightarrow -29 dB**

	TF (TP0-TP2) loss	TP2 ERL
CH 1	9.07 dB	10.61 dB
CH 2	9.29 dB	7.05 dB
CH 3	11.15 dB	10.92 dB
CH 4	11.15 dB	7.44 dB
802.3ck CR	< 10.975 dB	> 7.3 dB

C_p (fF)	TP2 ERL
87	7.4
150	7.3
200	7.1
250	6.9



Conclusion & Proposal

- ERL specification at TP2 is sufficient to constrain reflections which may cause severe degradation on COM
- This presentation shows that the residual ISI at TP2 will be affected by both TF loss & impedance discontinuities within TPO-TP2
 - Need to change the values of Np & ISI_RES (max) to
 - Distinguish residual ISI from TF loss and reflection
 - Differentiate TFs with different levels of impedance discontinuity
- Proposals
 - **Option A (preferred):** Remove ISI_RES specification from 802.3ck CR (Table 162.10)
 - **Option B:** Change Np from 11 → **18** & ISI_RES (max) from -30 dB → **-29 dB**

Option B	Np	RES_ISI (max)
CR	11	-30
Proposal	18	-29

Proposed Straw Poll

- I support the following direction for ISI_RES spec in 100Gbase CR
 - (A) Option A: Remove ISI_RES spec from 802.3ck CR (Table 162.10)
 - (B) Option B: Change N_p from 11 to 18 & ISI_RES (max) from -30 dB to -29 dB
 - (C) The draft ISI_RES method and spec limit for CR need improvement

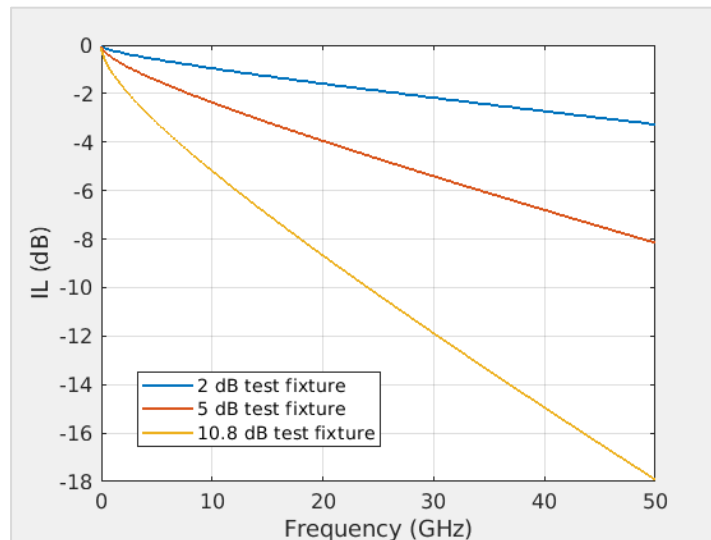
Appendix



2/5/10.8 dB Test Fixture

- TF generated based on reference PCB model
 - Impedance: 92.5 Ohm
 - 2/5/10.8 dB → 50/125/275 mm

Table 92-12 parameters		
Parameter	Setting	
<i>board_tj_gamma0_a1_a2</i>	[0 3.8206e-04 9.5909e-05]	
<i>board_tj_tau</i>	5.790E-03	ns/mm
<i>board_Z_c</i>	92.5	Ohm





COM Spreadsheet for TP2 Impulse Response Generation

Table 93A-1 parameters				I/O control			Table 93A-3 parameters		
Parameter	Setting	Units	Information				Parameter	Setting	Units
f_b	53.125	GHz			DIAGNOSTICS	1	logical	package_tl_gamma0_a1_a2	[0 0.0009909 0.0002772]
f_min	0.05	GHz			DISPLAY_WINDOW	0	logical	package_tl_tau	0.006141
Delta_f	0.01	GHz			CSV_REPORT	0	logical	package_Z_c	[87.5 87.5 ; 92.5 92.5]
C_d	[1.2e-4 0]	nF	[TX RX]		RESULT_DIR	.\results\100GEL_CR_CA_(date)\			
L_s	[0.12, 0]	nH	[TX RX]		SAVE_FIGURES	0	logical		
C_b	[0.3e-4 0]	nF	[TX RX]		Port Order	[1 3 2 4]			
z_p select	[1 2]		[test cases to run]		RUNTAG	CR_eval_			
z_p (TX)	[12 31; 1.8 1.8]	mm	[test cases]		COM_CONTRIBUTION	0	logical		
z_p (NEXT)	[0 0; 0 0]	mm	[test cases]		Operational				
z_p (FEXT)	[12 31; 1.8 1.8]	mm	[test cases]		COM Pass threshold	3	dB	board_tl_gamma0_a1_a2	[0 3.8206e-04 9.5909e-05]
z_p (RX)	[0 0; 0 0]	mm	[test cases]		ERL Pass threshold	8.25	dB	board_tl_tau	5.790E-03
C_p	[0.87e-4 0]	nF	[TX RX]		DER_0	0.0001		board_Z_c	100
R_0	50	Ohm			T_r	0.0075	ns	z_bp (TX)	110.3
R_d	[50 50]	Ohm	[TX RX]		FORCE_TR	1	logical	z_bp (NEXT)	110.3
A_v	0.413	V			Local Search	2		z_bp (FEXT)	110.3
A_fe	0.413	V			BREAD_CRUMBS	1	logical	z_bp (RX)	110.3
A_pe	0.608	V			SAVE_CONFIG2MAT	1	logical	C_0	[0.29e-4]
AC_CM_RMS	0	V	[test cases]	* 0.0235 0.0256	PLOT_CM	0		C_1	[0.19e-4]
L	4				TDR and ERL options			Include PCB	0
M	32				TDR	1	logical	Floating Tap Control	
filter and eq					ERL	1	logical	N_bg	3
f_r	0.75	*fb			ERL ONLY	0	logical	N_bf	3
c(0)	0.54	min			TR_TDR	0.01	ns	N_f	40
c(-1)	[-0.34;0.02;0]	[min;step;max]			N	800		brmax	0.05
c(-2)	[0;0.02;0.12]	[min;step;max]			beta_x	0		B_float_RSS_MAX	0.02
c(-3)	[-0.06;0.02;0]	[min;step;max]			rho_x	0.618		N_tail_start	25
c(1)	[-0.2;0.02;0]	[min;step;max]			fixture delay time	[.2e-9 0]	* port1 port2	ICN parameters	
N_b	12	UI			TDR_W_TPKG	1		f_v	0.594
b_max(1)	0.85				N_bx	0	UI	f_f	0.594
b_max(2..N_b)	[0.3 0.2 *ones(1,5) 0.1 *ones(1,5)]				Tukey_Window	1	logical	f_n	0.594
b_min(1)	0.3				Noise, jitter			f_2	40.000
b_min(2..N_b)	[0.05 -0.03 *ones(1,10)]				sigma_BJ	0.01	UI	A_ft	0.600
g_DC	[-20;10]	dB	[min;step;max]		A_DD	0.02	UI	A_nt	0.600
f_z	21.25	GHz			eta_0	9.00E-09	V^2/GHz	Receiver testing	
f_p1	21.25	GHz			SNR_TX	32.5	dB	RX_CALIBRATION	0
f_p2	53.125	GHz			R_LM	0.95		56GPAM4/matlab_mv/112G_CA	5.00E-03
g_DC_HP	[-6;1;0]		[min;step;max]						
f_HP_PZ	0.6640625	GHz							



TP0-TP2 Channel List

Contribution	Company		s4p	Manufacturing Variations	TP0-TP2 (dB)	TP2 ERL (dB)
Presentation: 100 GEL C2M Flyover Host Files: Tp0 to Tp2, with and without manufacturing variations, for losses of 9, 10, 11, 12, 13, and 14 dB Losses S-parameter files: C2M channels and xtalk (all lengths and variations)	Samtec	CH 1	C2M_Z100_IL9_BC-BOR_N_N_N_THRU	Normal	9.07	10.61
		CH 2	C2M_Z100_IL10_WC-BOR_H_L_H_THRU	Worst case	9.29	7.05
		CH 3	C2M_Z100_IL11p2_BC-BOR_N_N_N_THRU	Normal	11.15	10.92
		CH 4	C2M_Z100_IL12_WC-BOR_H_L_H_THRU	Worst case	11.15	7.44
802.3ck CR					< 10.975	> 7.3

System Topology Overview: C2M using FLYOVER Cable

